

The Belle II pixel vertex detector

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On behalf of the DEPFET Collaboration

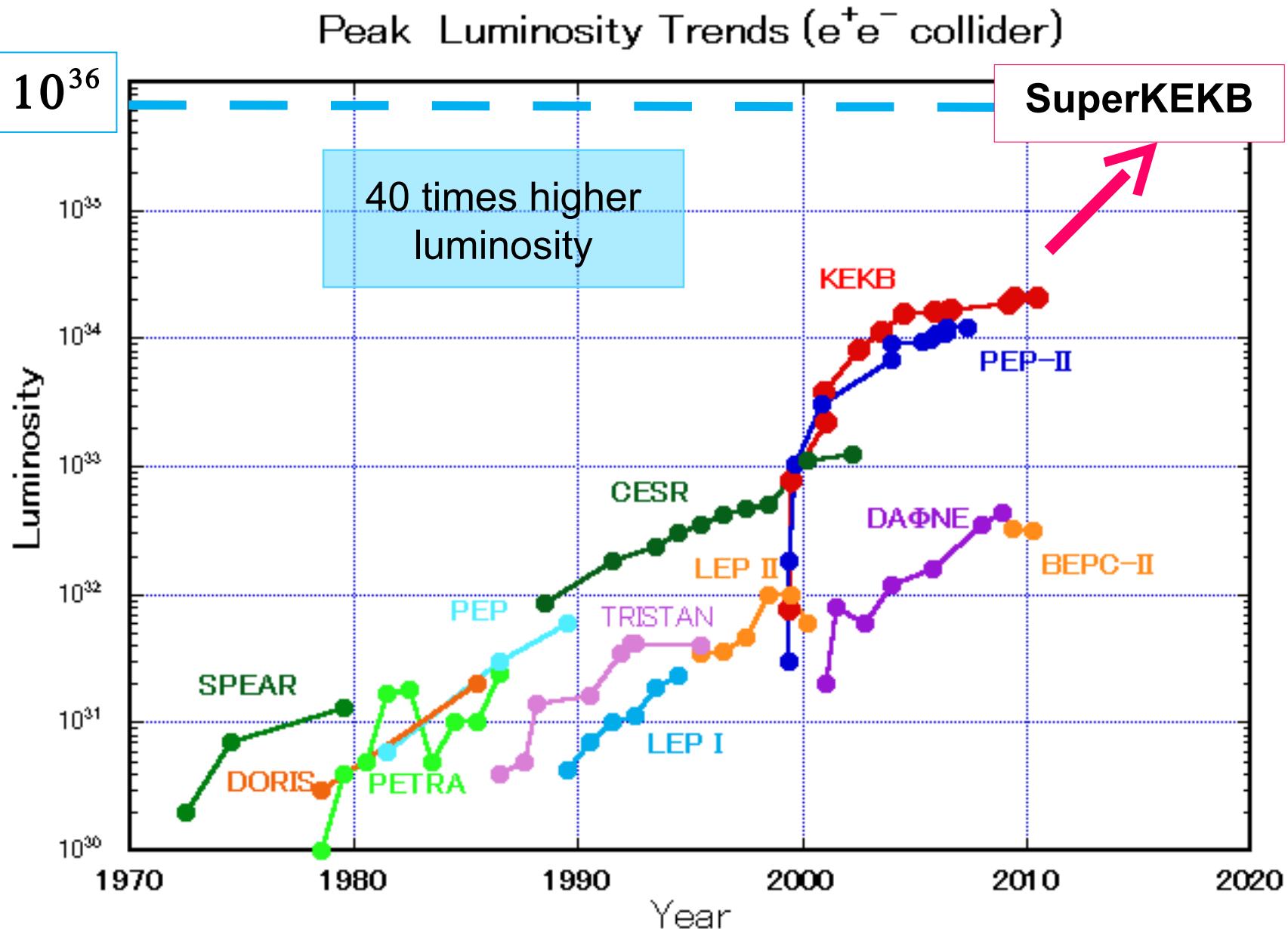


The International Workshop on Radiation Imaging Detectors
ETH Zurich, 3-7 July 2011

Outline

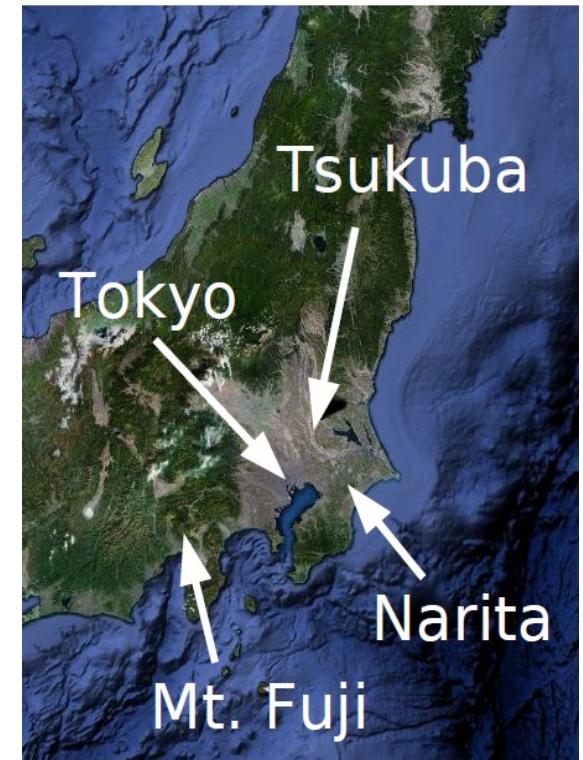
- *Upgrade KEKB to Super KEKB*
 - Belle II detector design
- *DEPFET principle*
 - Readout sequence
- *DEPFET ladder design for Belle II*
- *Readout ASICS*
 - DCD
 - Switcher-B
 - DHP
- *Prototyping for Belle II*
- *Test results*
- *Conclusion*

Next generation B-factories





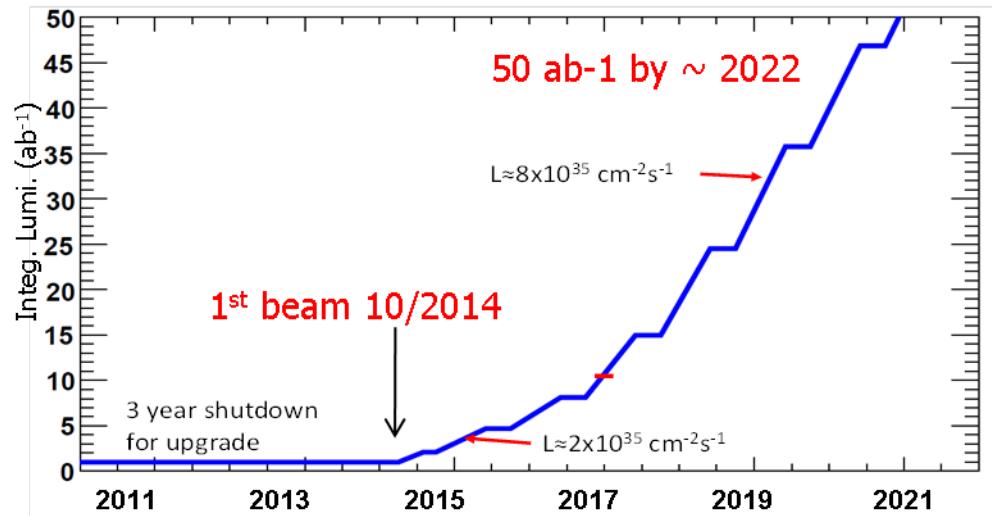
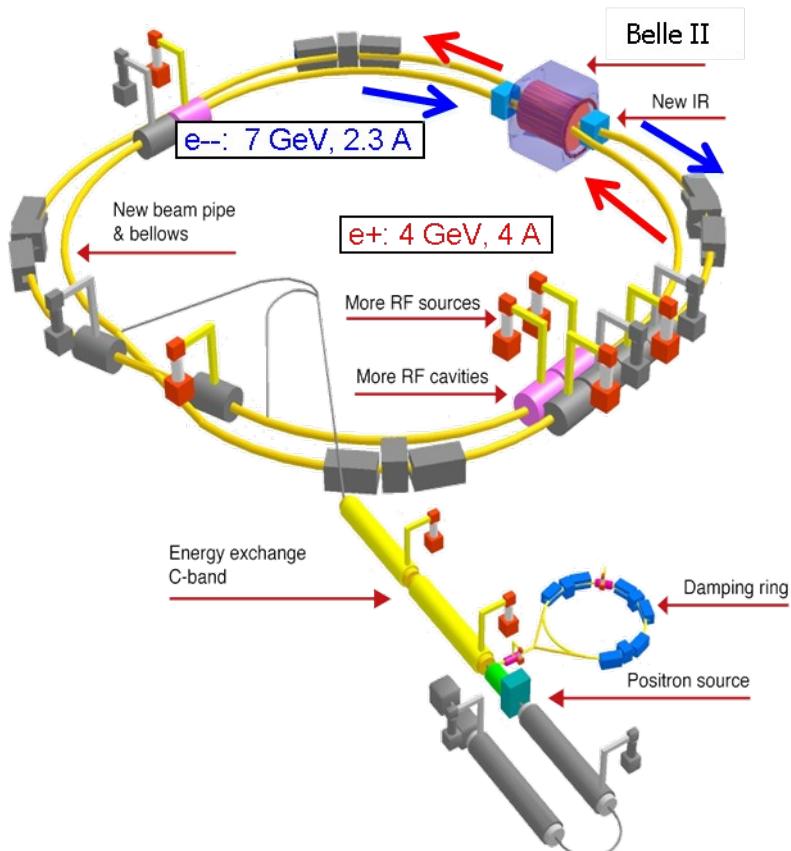
B-factory in Tsukuba, Japan



World record luminosity for e+e- colliders: $2.1 \times 10^{34} \text{ cm}^{-2}\text{s}^{-1}$

KEKB to SuperKEKB

- e^-/e^+ , 7 GeV & 4 GeV
- E_{cm} at $\Upsilon(4s)$ resonance, (10.58 GeV)
- goal $L = 8 \times 10^{35} \text{ cm}^{-2}\text{s}^{-1}$



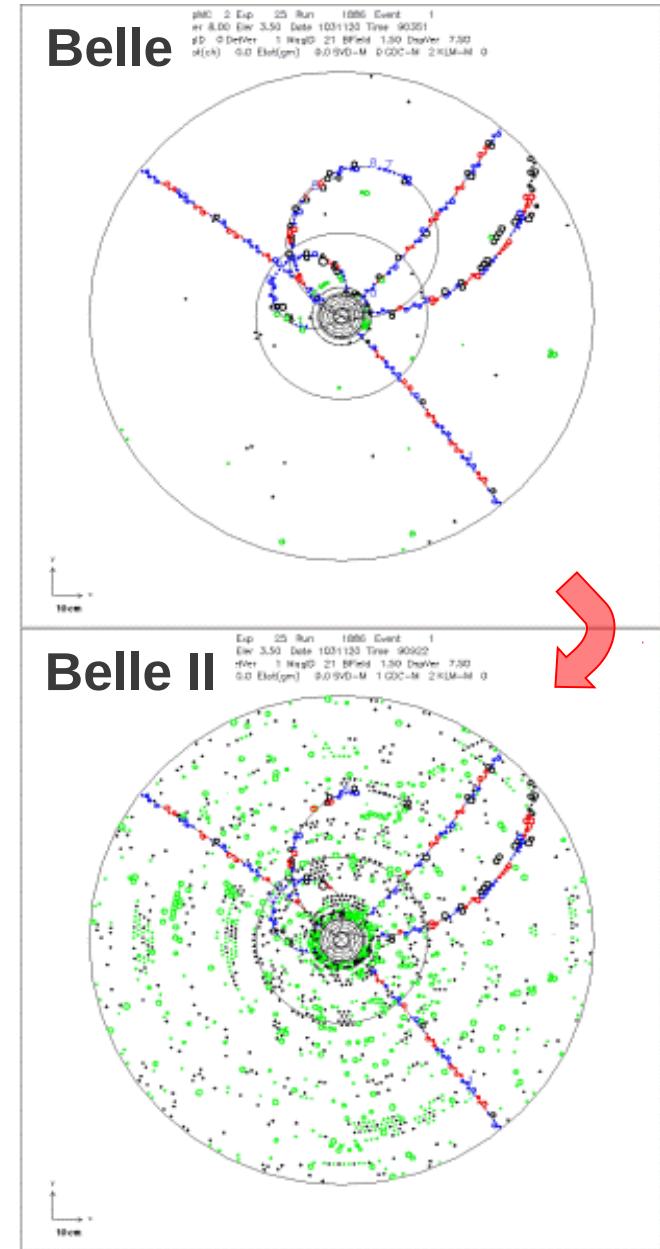
Machine parameter	HER (KEKB)	LER (KEKB)	HER (SuperKEKB)	LER (SuperKEKB)
Vertical beam size	$0.94\mu\text{m}$	$0.94\mu\text{m}$	59nm	59nm
Beam current(mA)	1188	1637	2600	3600
luminosity($\text{cm}^{-2}\text{s}^{-1}$)	2.1×10^{34}		8×10^{35}	

Smaller beam size & more current:
→ 40x higher luminosity

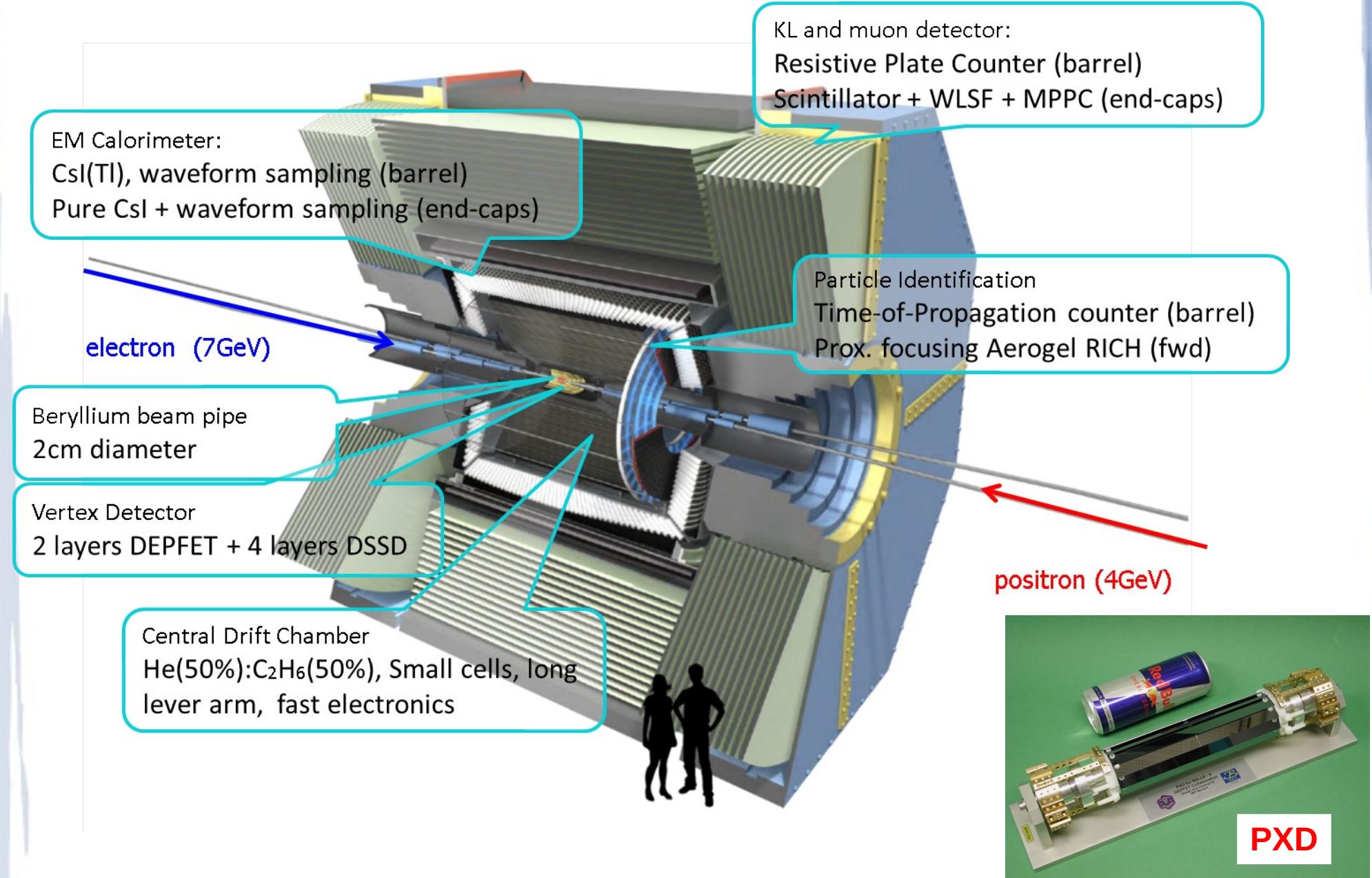
Requirements for the Belle II detector

- *Higher background (x10-20 compared to Belle)*
 - Radiation damage and occupancy
 - Fake hits
- *Higher event rate*
 - Higher trigger rate (0.5 kHz → 20-30 kHz)
- *The physical goals require a vertex detector with unprecedented performance ($\sim 10\mu m$) :*
 - low material budget ($< 0.2 X_0$ per layer)
 - high granularity pixel detector

New pixel vertex detector (PXD) based on DEPFET technology is being developed, using sensor thinned down to 75 μm .

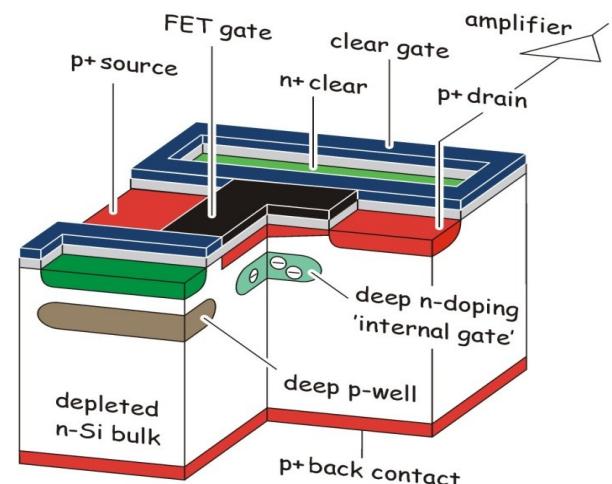
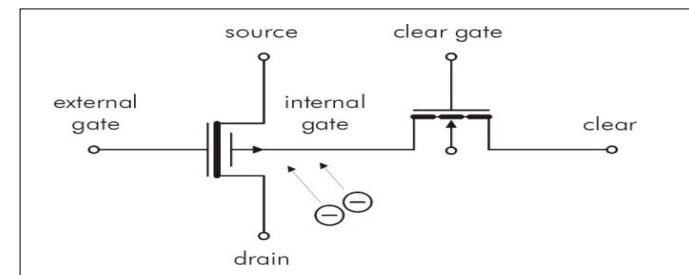
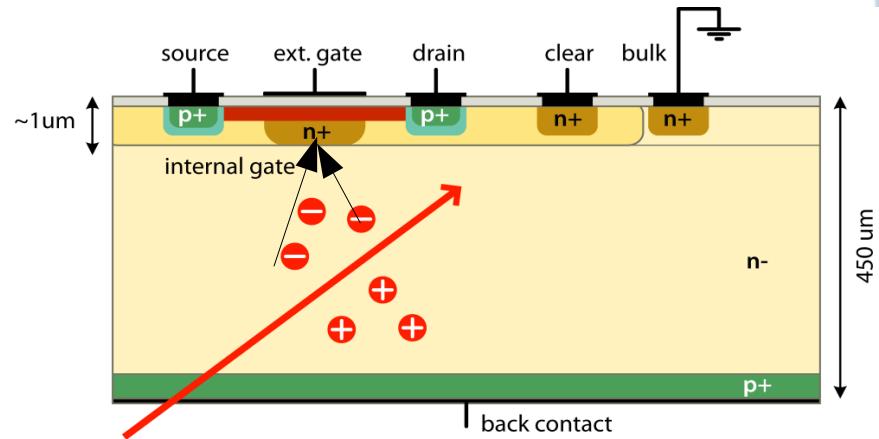


Belle II design



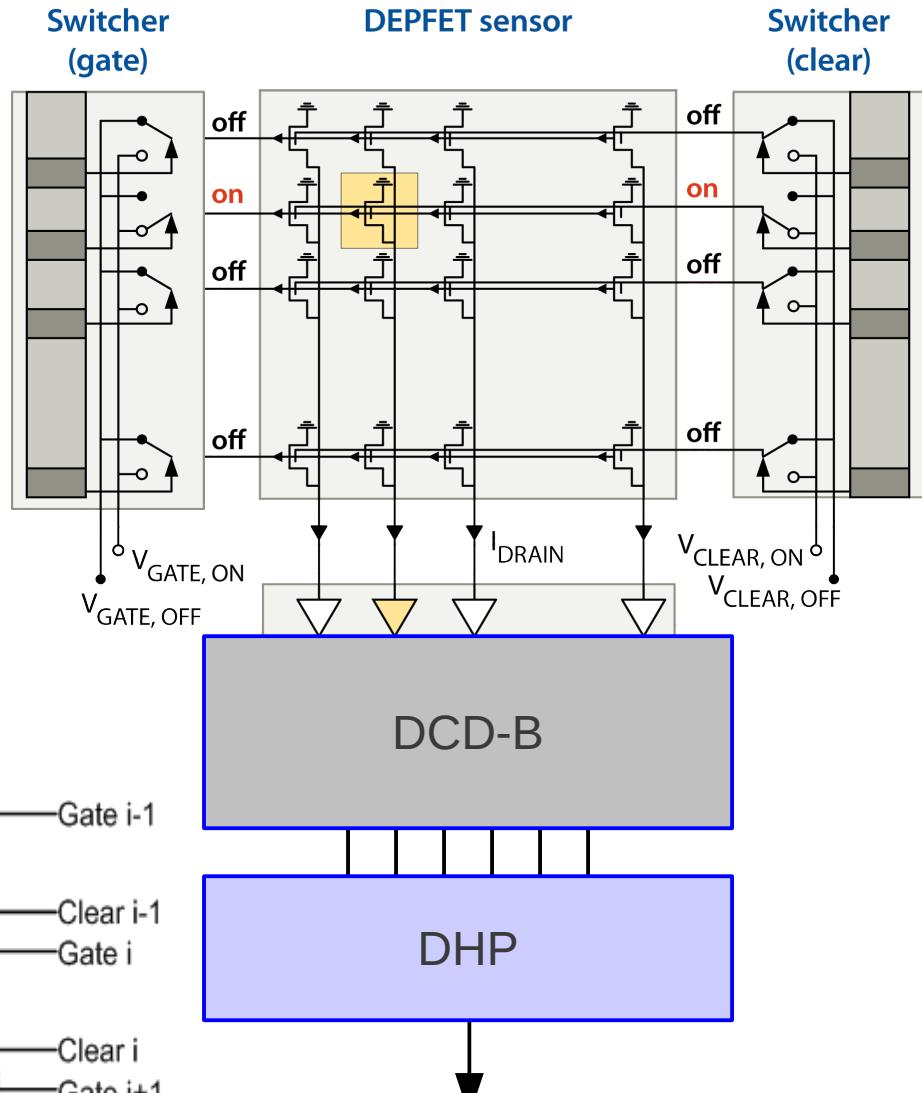
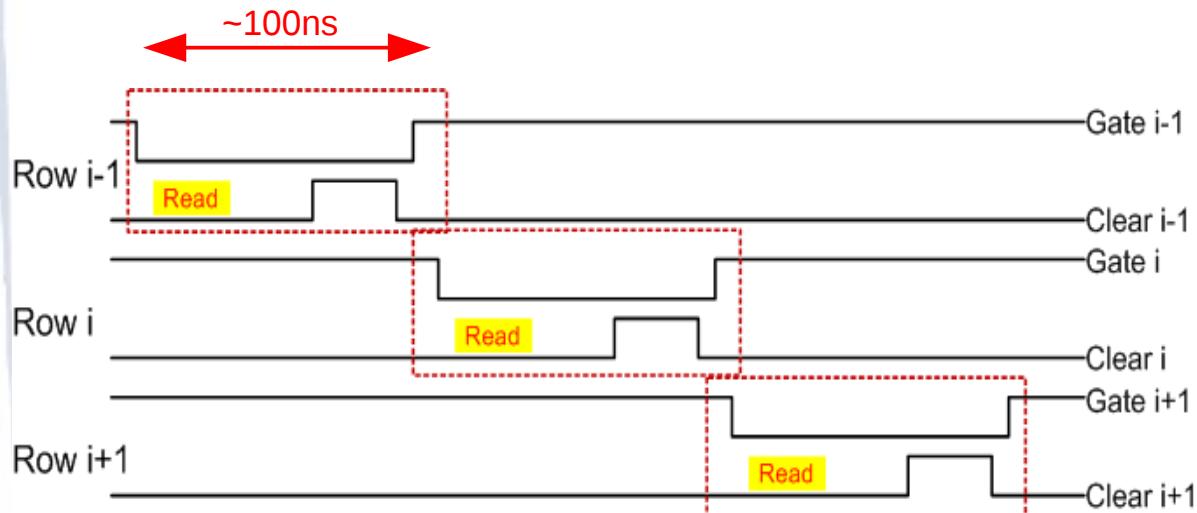
DEPFET principle

- The DEPFET is an active pixel sensor which integrates a MOSFET into the high resistivity silicon substrate
 - in-pixel amplification
- Provides fast charge collection in fully depleted bulk
 - fast signal rise time (~ns), small cluster size
- Electrons are collected in “internal gate” - potential minimum for electrons - and modulate transistor current
 - charge-to-current conversion
- Transistor can be switched off by external GATE – charge collection still active !
 - potentially low power device
- Low readout capacitance – reduces the noise
- no stitching, 100% fill factor
- no charge transfer needed
 - faster read out
 - better radiation tolerance
- Charge from internal gate is removed by the CLEAR contact



DEPFET readout sequence

- Row wise readout (Rolling Shutter)
- The SWITCHER chip generates the steering signals for the rows - **GATE** and **CLEAR**.
- Readout chip processes all columns in parallel
- DEPFET readout sequence (single sampling) :
 1. select row with external gate
 2. **readout** transistor current
 3. clear charge from internal gate
 4. select next row



PXD layout in GEANT4



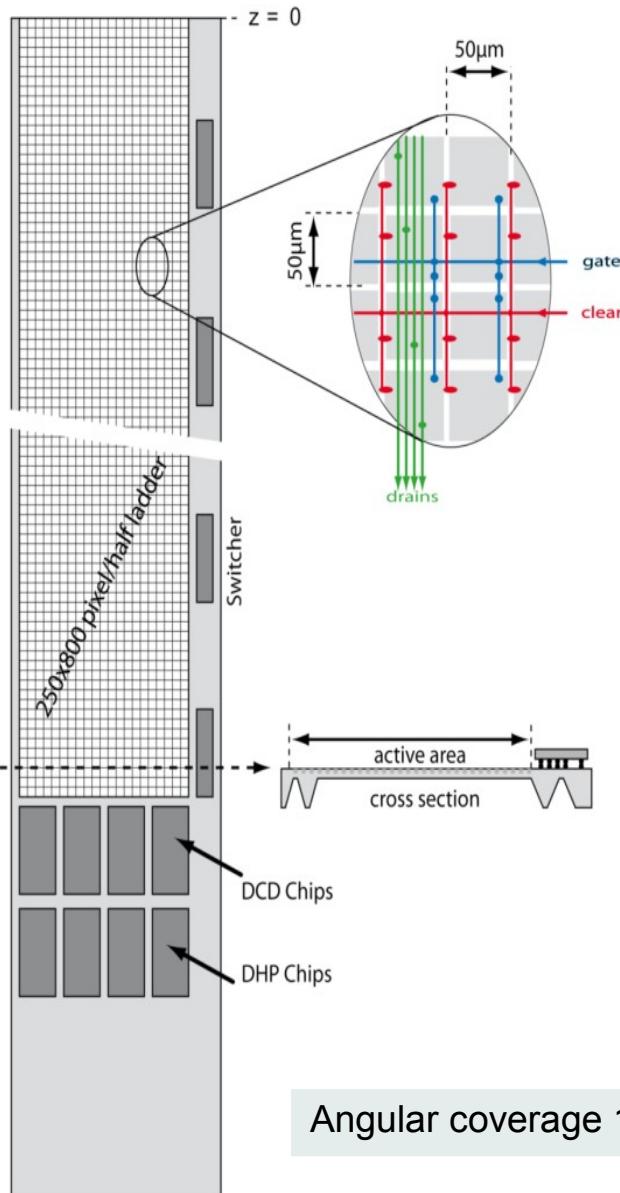
PXD ladder



Mechanical mockup



Belle II ladder



- All silicon module, sensitive area thinned
- Length: 90mm (inner), 123mm (outer)
- 23mm insensitive silicon on both sides
- Insensitive part is used as substrate for ASICs
- ASICs bump bonded to silicon substrate

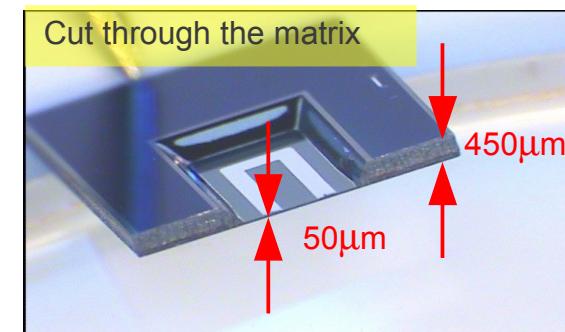
	Inner layer	Outer layer
# ladders	8	12
Radius	1.4 cm	2.2 cm
Pixel size	50x50 µm ²	50x75 µm ²
# pixels	1600(z)×250(R-φ)	1600(z)×250(R-φ)
Thickness	75 µm	75 µm
Frame/row rate	50 kHz/10 MHz	50 kHz/10 MHz

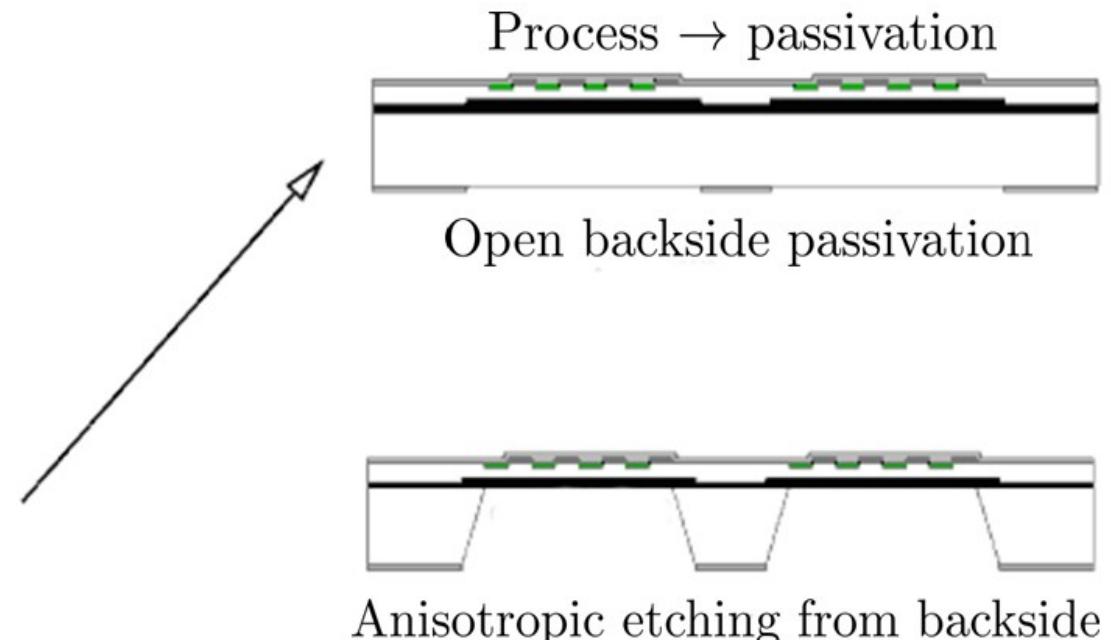
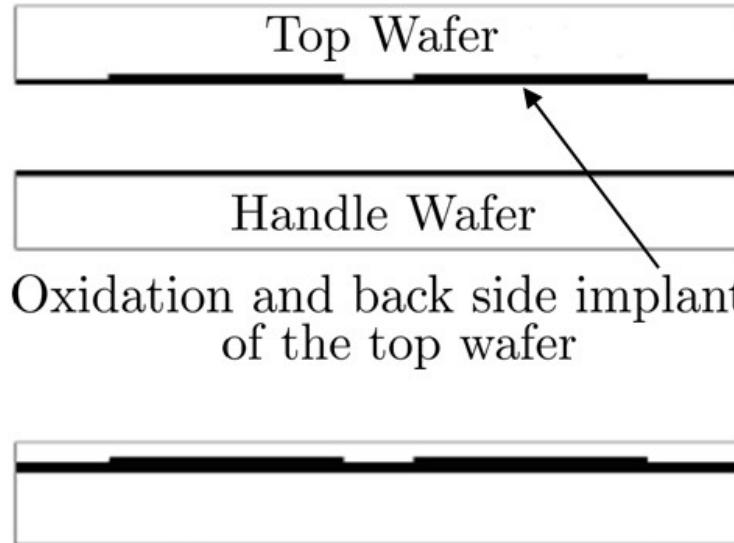
**Belle II PXD
in total ~8 Mpixels**

Self-supporting All-Silicon Module



- › Half-ladders (modules) are laser-cut
- › Modules are supported by a monolithic silicon frame
- › Two modules are assembled to one ladder
- › overall length is 136 mm (inner) and 169 mm (outer)

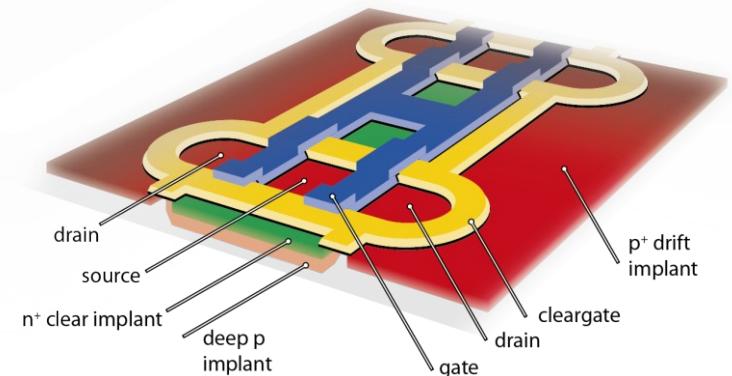
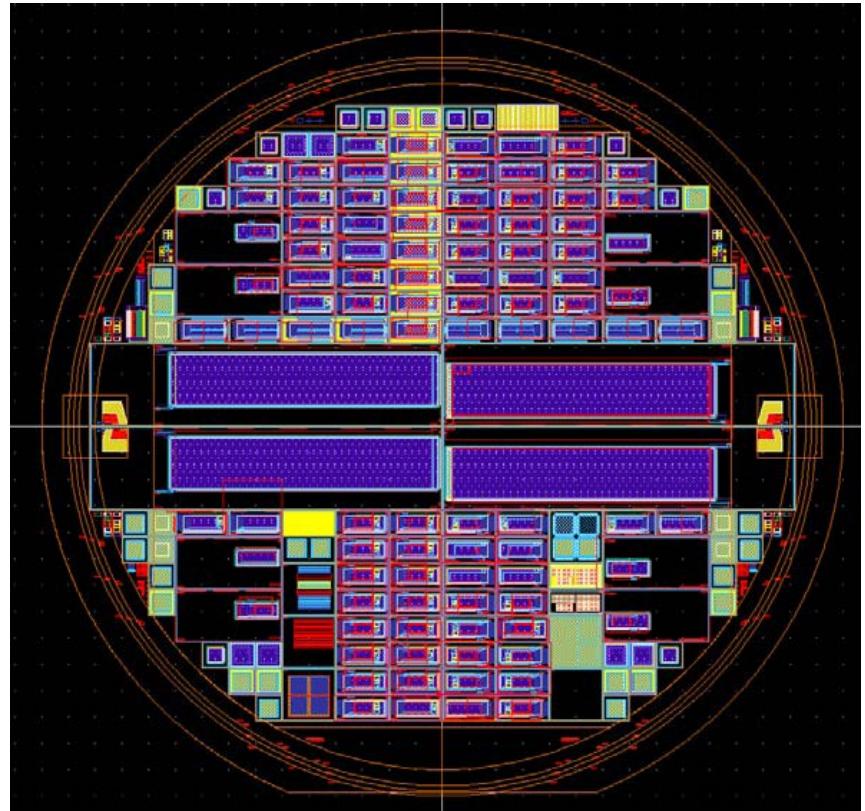




- *The DEPFET thickness becomes a free parameter, adjustable to the needs of the experiment!*
- *Key Process Modules:*
 - Wafer Bonding and thinning of top layer (external)
 - Sensor fabrication on SOI
 - Etching of the Handle Wafer
 - Litho on extreme topographies

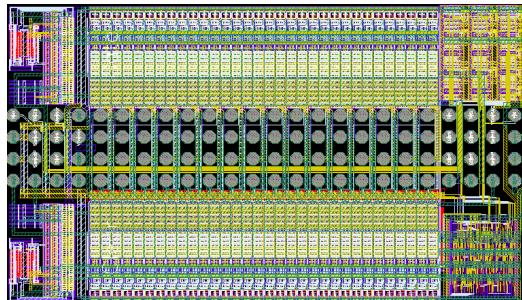
PXD6 prototyping

- 8 SOI wafers (50 µm top layer, 400 µm handle wafer)
 - + 2 reference wafers on std. 450µm material
- Pixel design and material adapted to 50 µm top layer thickness ($V_{fd} \approx 15V$), extensive device simulations to find the right geometry for the optimal electric field shape
- About 100 test matrices in different variations
 - pixel sizes from 20 µm to 200 µm
 - shorter gate length,
 - improved clear structures,
 - various field shapes..
- Technology variations on the wafer level (new dry etch techniques..)
- 4 half-ladders for Belle II with the most promising design options



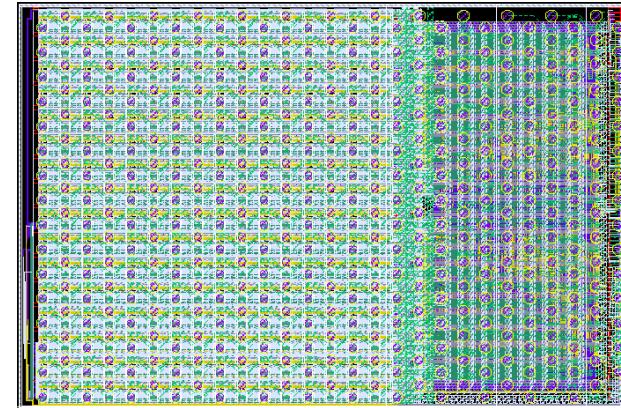
Readout ASICs

SwitcherB
Row control

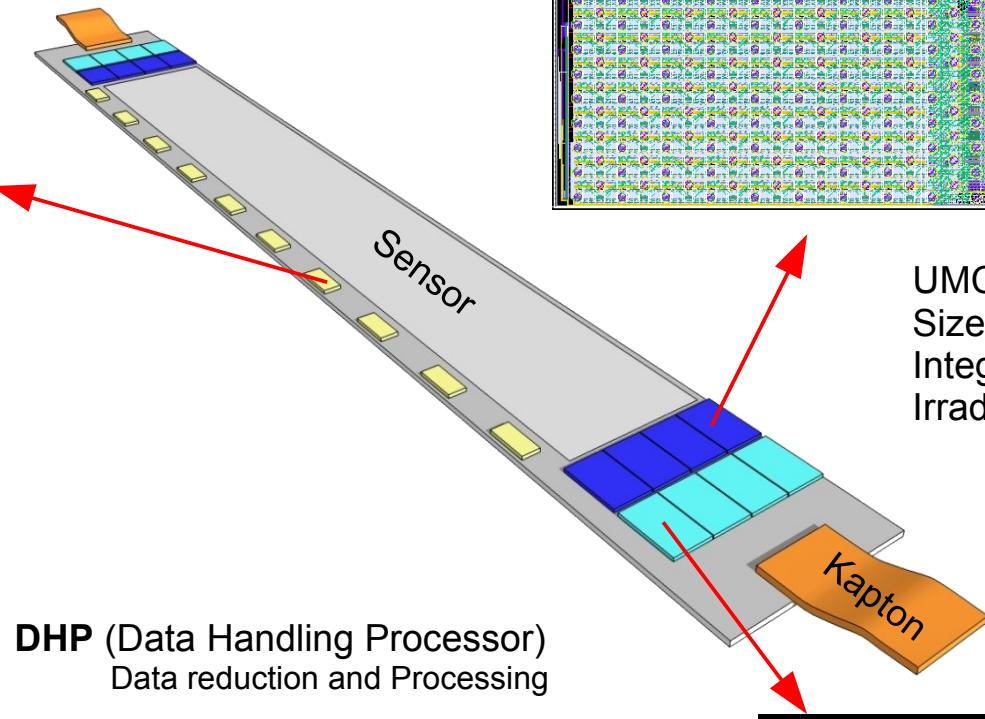


AMS high voltage 0.35μm
Size 3.6 x 2.1 mm²
Gate and Clear signal
Fast HV up to 30V
Rad. Hard proven (36Mrad)

DCDB (Drain Current Digitizer for BelleII)
Analog frontend and ADC

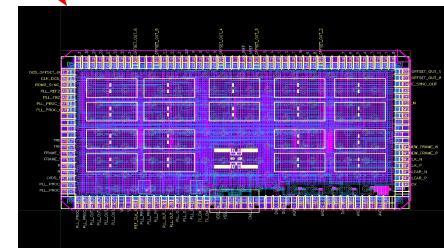


UMC 180nm
Size 3.3 x 5.0 mm²
Integrated ADC
Irradiation up to 7Mrad



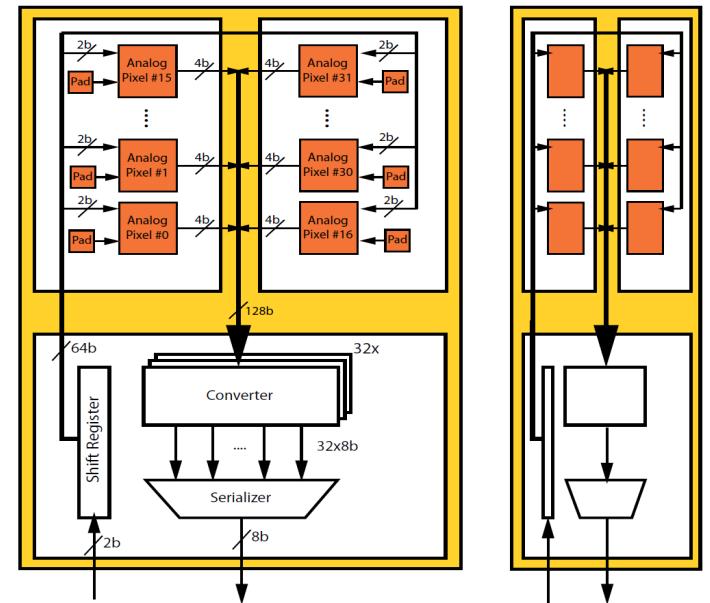
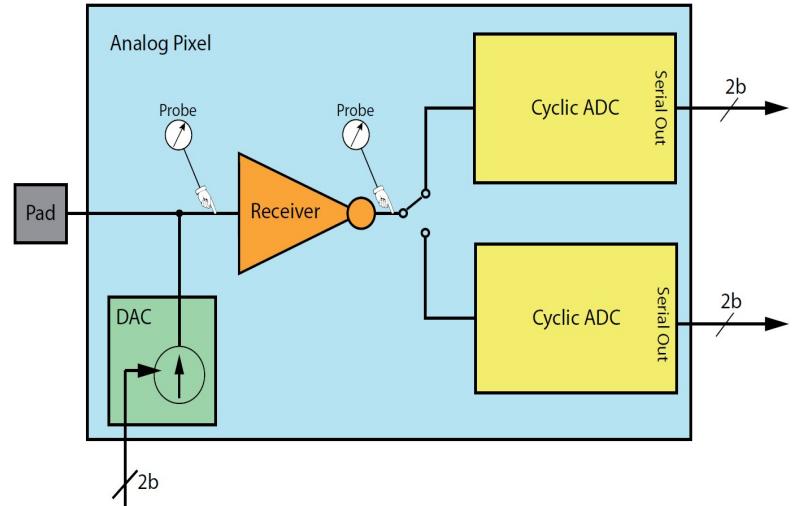
DHP (Data Handling Processor)
Data reduction and Processing

IBM CMOS 90nm → TSMC (65nm)
Stores raw data and pedestals
Common mode and pedestal correction
Data reduction (zero suppression)
Timing signal generation

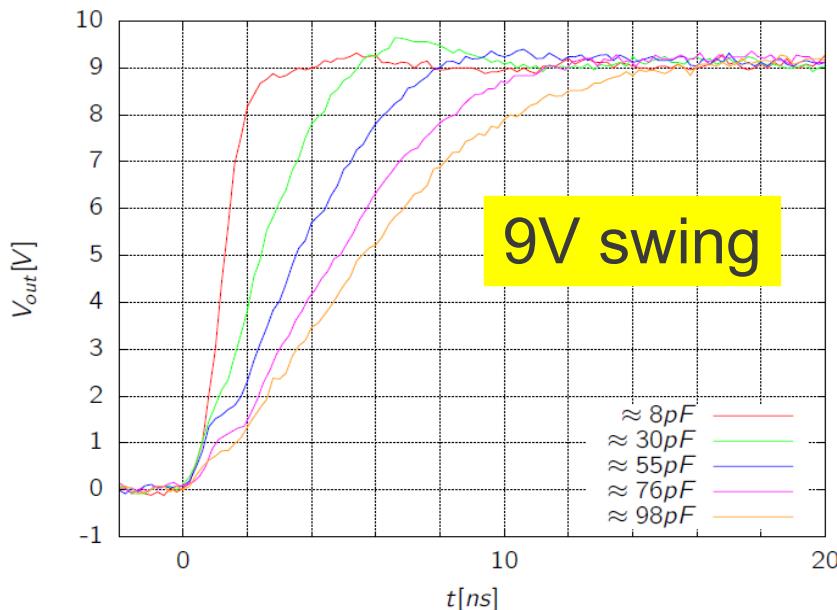
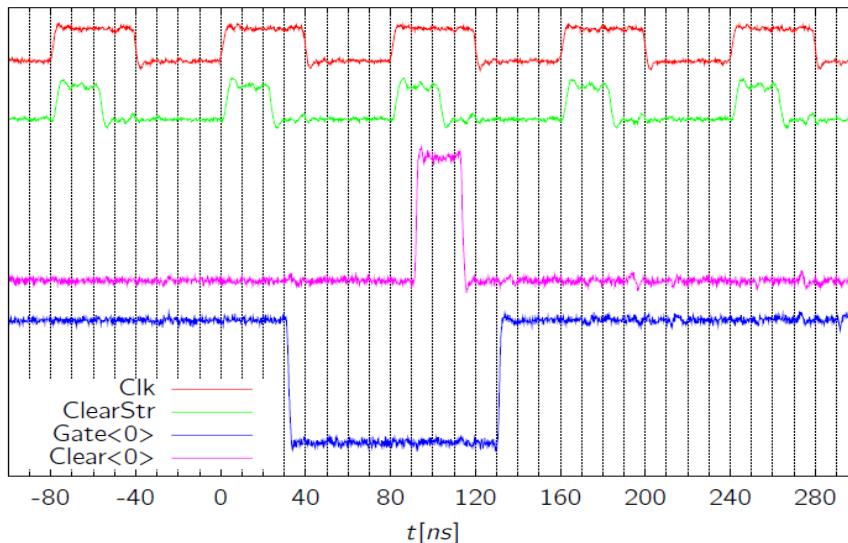


Switcher, DCDB: Heidelberg U.
DHP: Bonn U., Barcelona U.

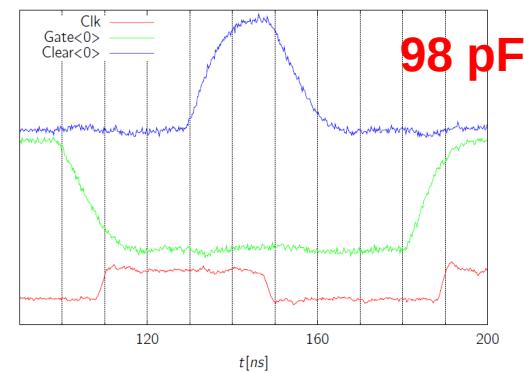
- Chip size: $3240 \mu\text{m} \times 4969 \mu\text{m}$
- Total: 416 bumps
 - 256 analog inputs
 - 64 digital outputs (8 times 8-bit at 350 MHz) for ADC codes
- 8-bit ADC precision
- Sampling period: $\sim 92 \text{ ns}$ (350 MHz)
- Every analog channel contains:
 - Current receiver, based on a trans-impedance amplifier with output resistor, with variable gain and shaping time
 - 8-bit current-mode ADC (two per channel)
- Global circuits:
 - Synthesized digital readout block for ADC-data processing, multiplexing and sorting
 - JTAG
- Single-ended digital outputs for 400 Mbit/s
- Supply current:
 - Analog: 300-500 mA
 - Digital: 300 mA



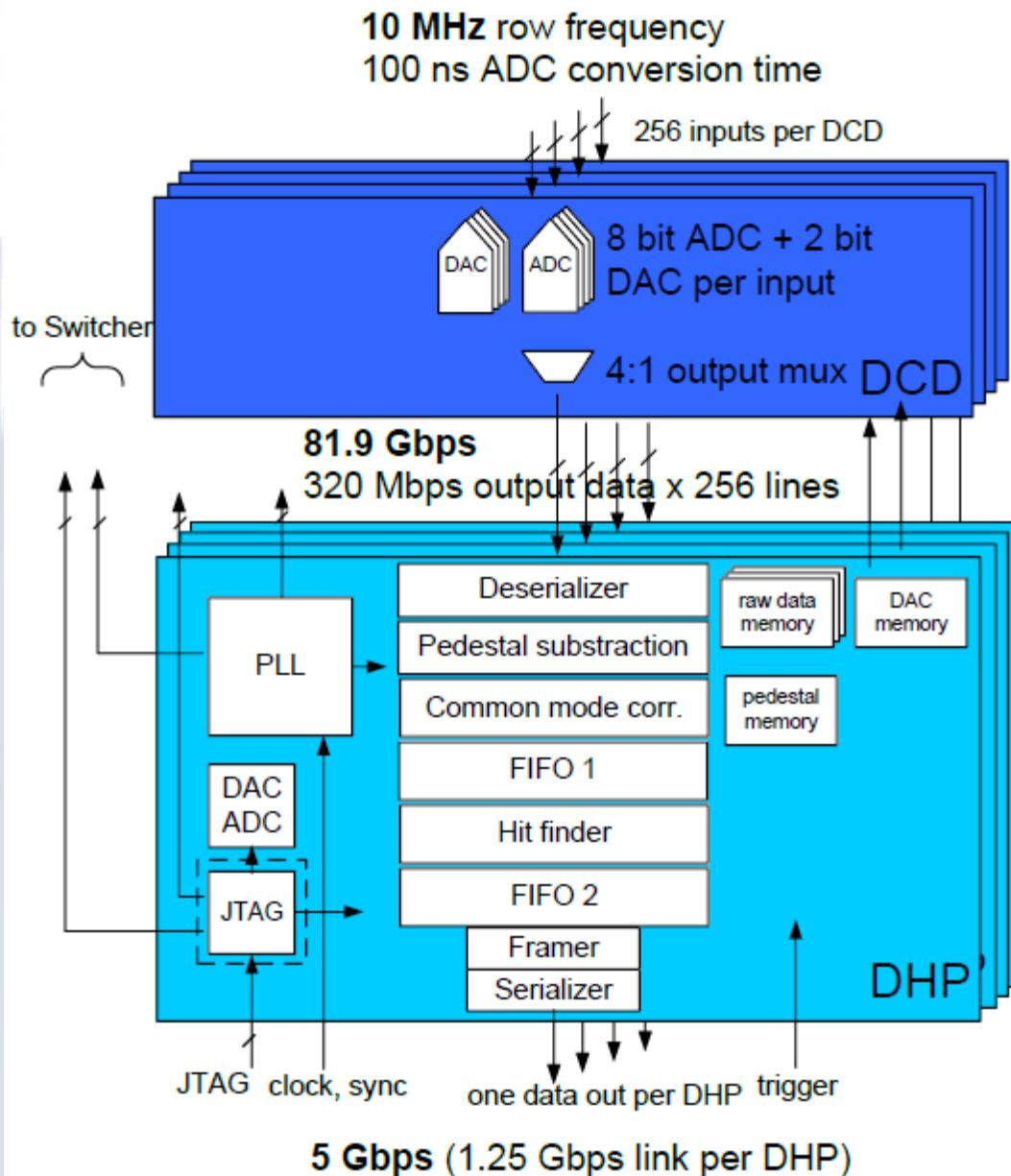
Switcher B



- Designed size: $2100\mu\text{m} \times 3600\mu\text{m}$
- 32 rows
 - each row with CLEAR and GATE output
 - shift register to enable rows (LVDS)
 - gate and clear strobe signals (LVDS)
 - sleep and boost states for power saving
- AMS HV technology (max 50V)
- Radiation hard design
 - Chip works after 24.5Mrad irradiation
- floating digital 3.3V supply
- JTAG slow control and boundary scan
 - 1.8V capable I/Os
- Switcher-B working at 80ns row time

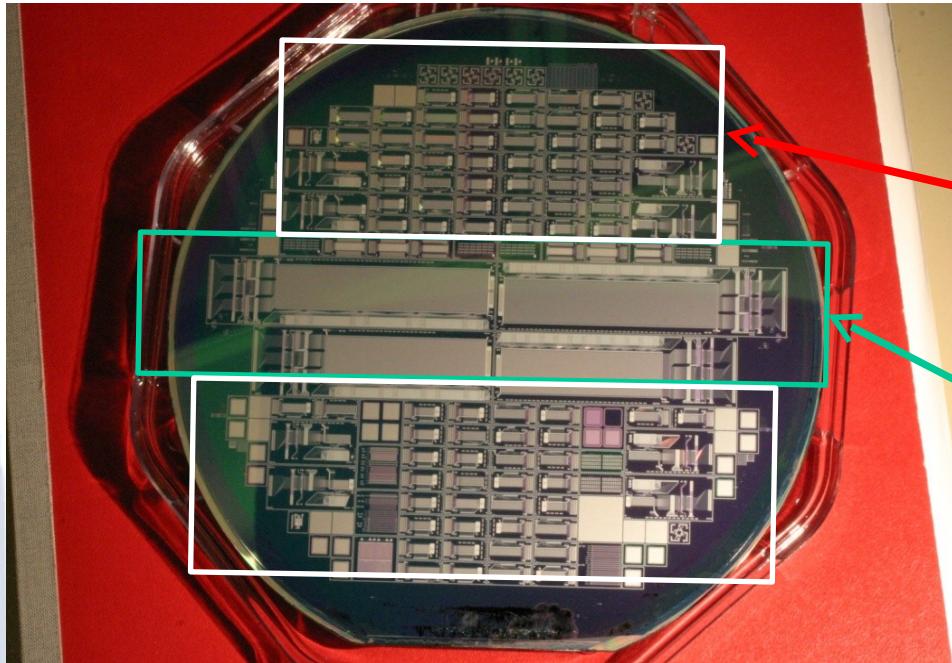


DHP Function Blocks



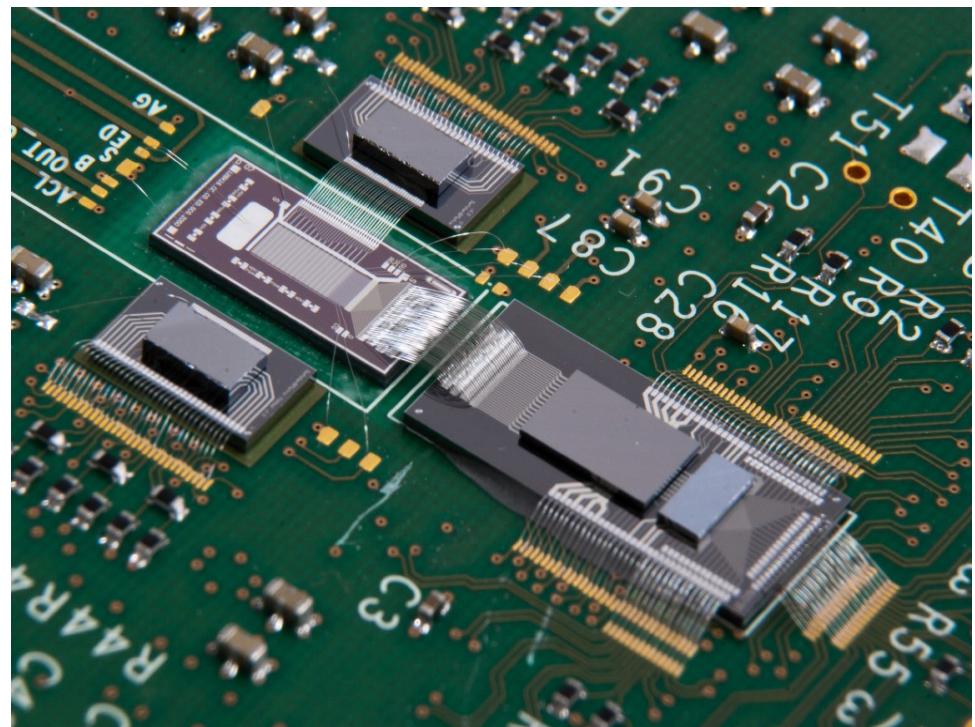
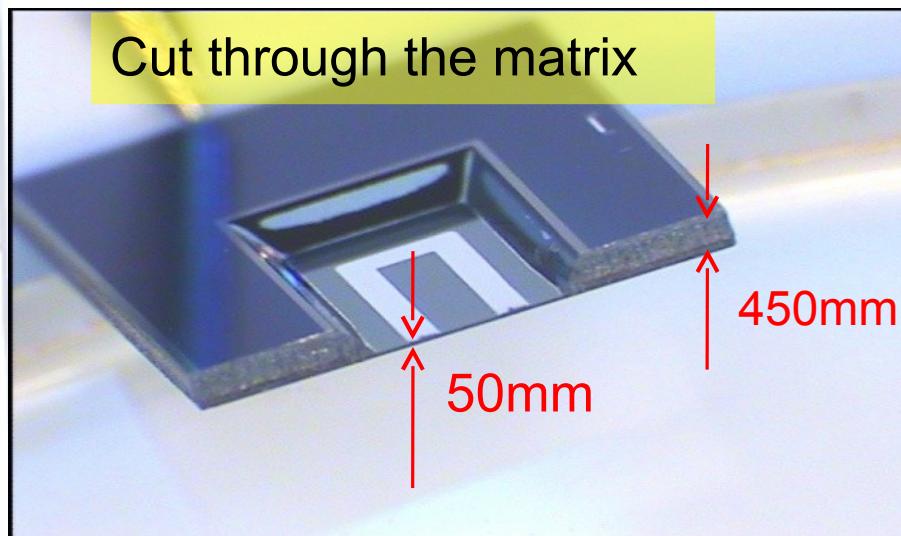
- 64 inputs at 400MHz input rate
- 50kHz input frame rate
- 30kHz trigger rate
- Receive and write raw data to memories (continuously)
- Trigger → read memory and process data
- Pedestal subtraction
 - Static pedestals (update via JTAG)
- Two pass common mode correction
 - First pass: all pixels → find hits (biased)
 - Second pass: average w/o hits → zero-sup.
- Hit finder & de-randomizing FIFOs
 - 64 inputs (FIFO 1)
 - 1 output (FIFO 2)
- Framer
 - Data formatting
 - AURORA protocol
- Serializer
 - 20:1 mux
 - CML driver with pre-emphasis @1.5Gbps

First measurements of thin matrix



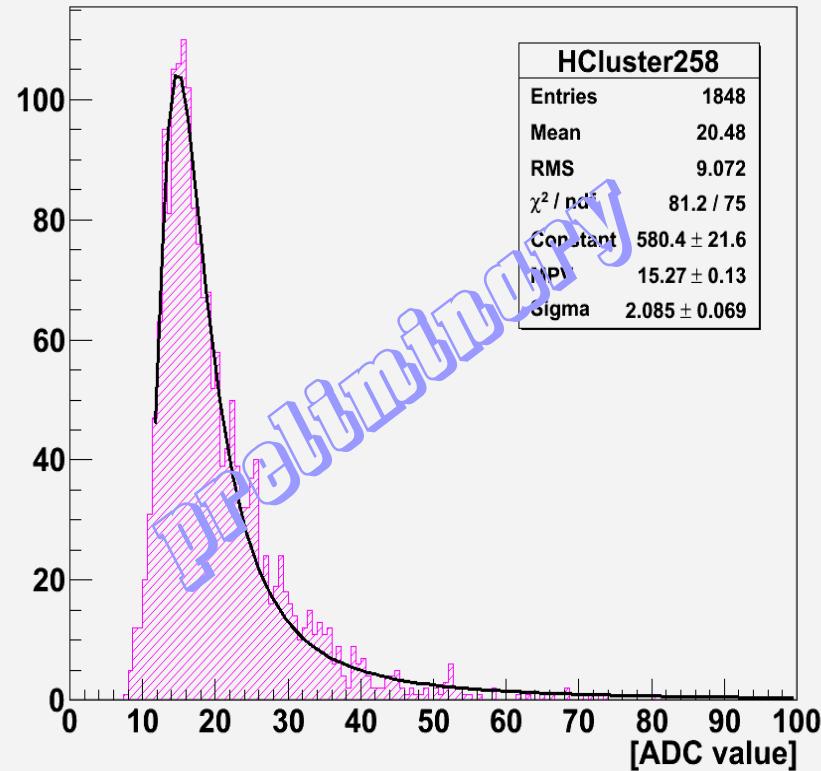
Small matrices 32x64 pixels,
different technology variations,
ASIC connection via wire bonding

**Half ladders 768x120-160 pixels
(~ Belle II geometry)**

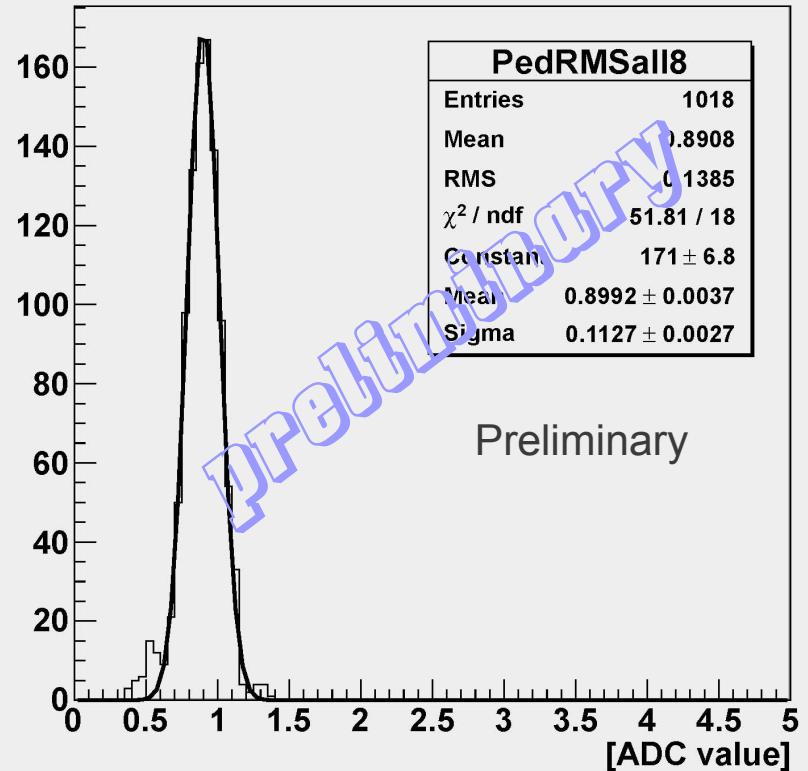


- ^{90}Sr source
- DCD-B readout @ 320 MHz = 100 ns row readout
- S/N = 17 – without optimization of DEPFET voltages

Cluster 5x5 (Mod8)(RunNo3018)

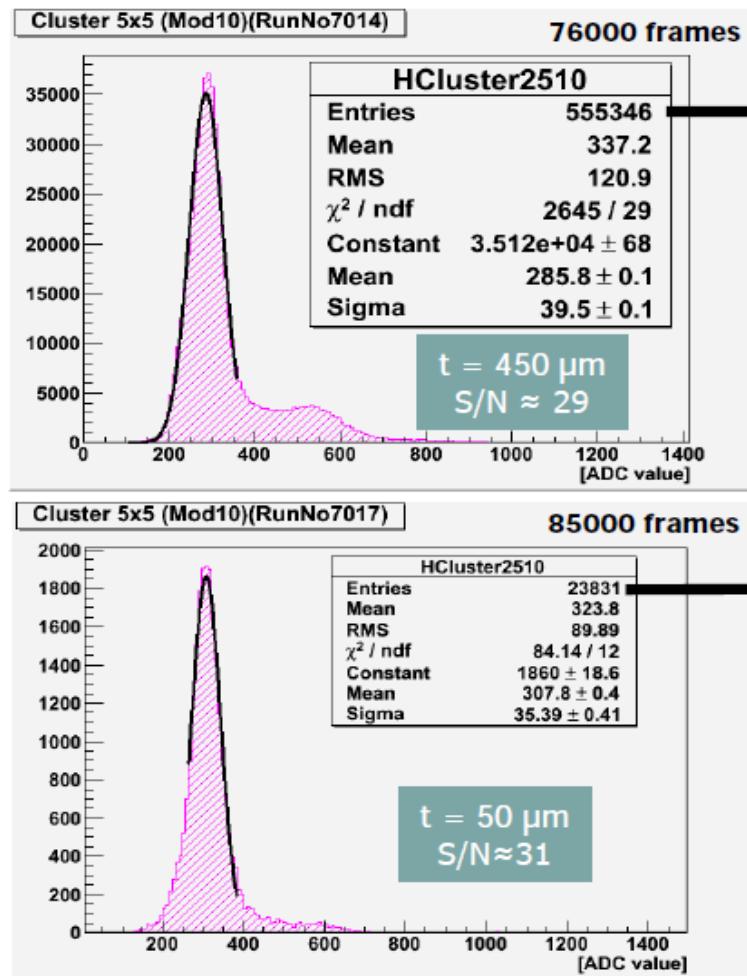


Noise distribution (Mod8)



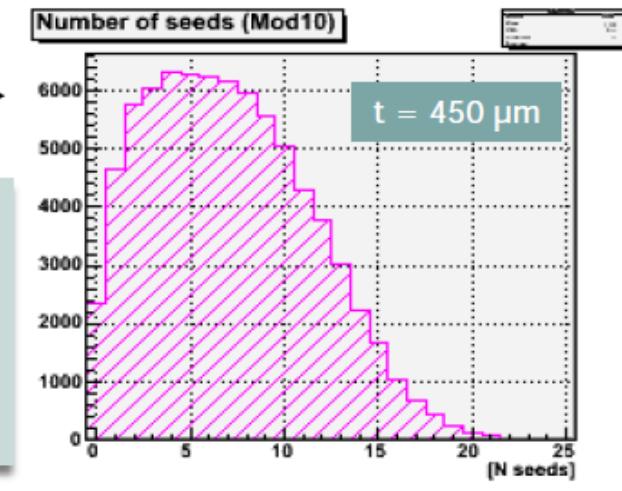
Signal measurements ^{109}Cd

- 2 DUTs: 32x64 pixels Belle II PXD design, $L=6\ \mu\text{m}$, pixel size $50\times 75\ \mu\text{m}^2$, same design on front (CURO readout chip)
 - I : 450 μm standard
 - II: 50 μm SOI

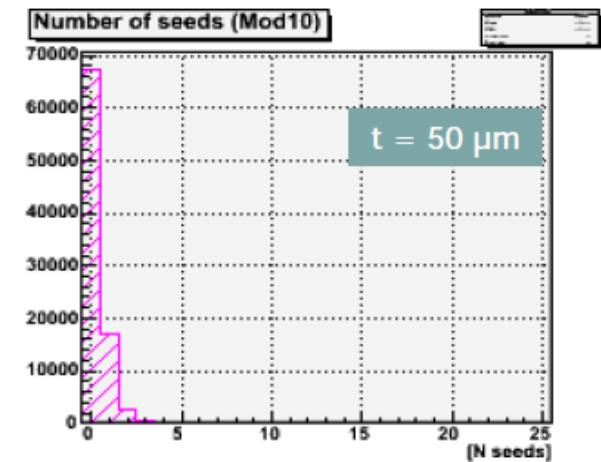


Thick: 7 clusters/frame

- ▷ 22keV photons
- ▷ ~ 6000 e/h pairs
- ▷ does not depend on t !
- ▷ but count rate is reduced
- ▷ photons just pass w/o conversion

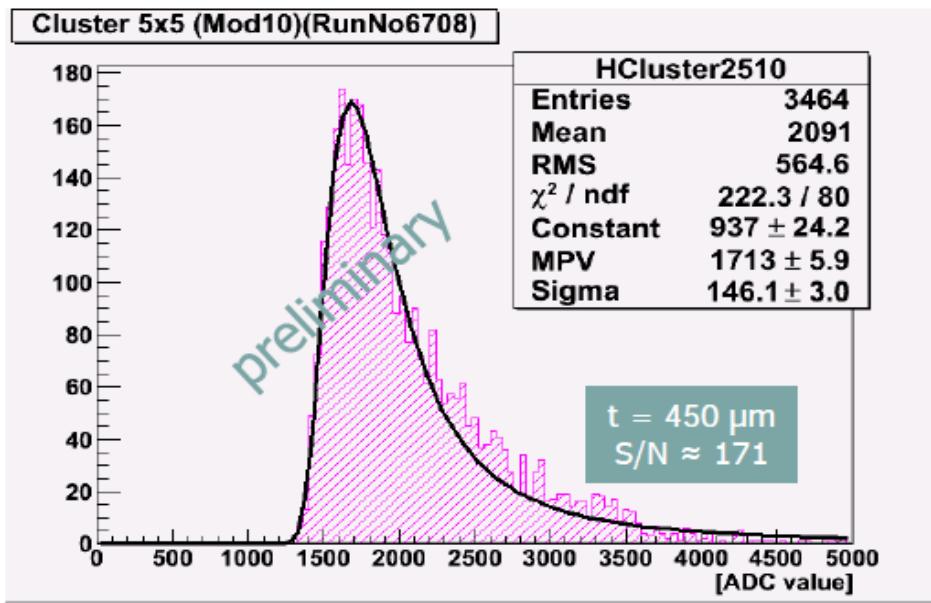


Thin: 0.28 clusters/frame



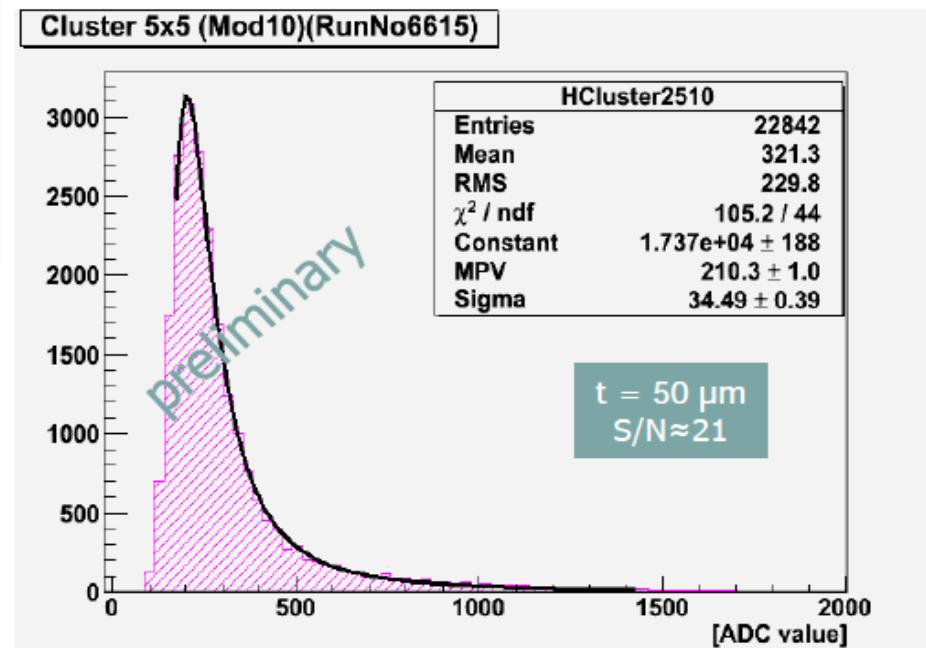
Signal measurements ^{90}Sr

- 2 DUTs: 32x64 pixels Belle II PXD design, $L=6\ \mu\text{m}$, pixel size $50\times 75\ \mu\text{m}^2$, same design on front, (CURO readout chip)
 - I: $450\ \mu\text{m}$ standard
 - II: $50\ \mu\text{m}$ SOI



- ▷ from Cd90 we know: 1 ADU $\rightarrow 19.8\ \text{e}^-$
- ▷ Sr90 signal with 50 μm : 210 ADU $\rightarrow 4164\ \text{e}^-$
- ▷ expect $\sim 80\text{e}^-/\mu\text{m}$ for a mip: $\sim 4000\ \text{e}^-$ for 50 μm
- ▷ signal(450 μm) : signal(50 μm): 8.2

- ▷ β source, $\sim 2\text{MeV}$ end energy, close to mip
- ▷ photons and LE e^- blocked by 4.3 mm plastic
- ▷ external scintillator trigger below the sensor



Conclusion

- DEPFET is the baseline technology for Belle II PXD
- The high-precision, low mass DEPFET Pixel Detector is in the construction phase
- The first thinned sensor prototypes are currently being tested
 - target read out time of 100ns/row is achieved
 - test shows that thin DEPFET have expected performance.
- This project gives a strong push for the DEPFET for future e+e- colliders
 - many techniques developed for Belle II are also applicable at future e+e- colliders

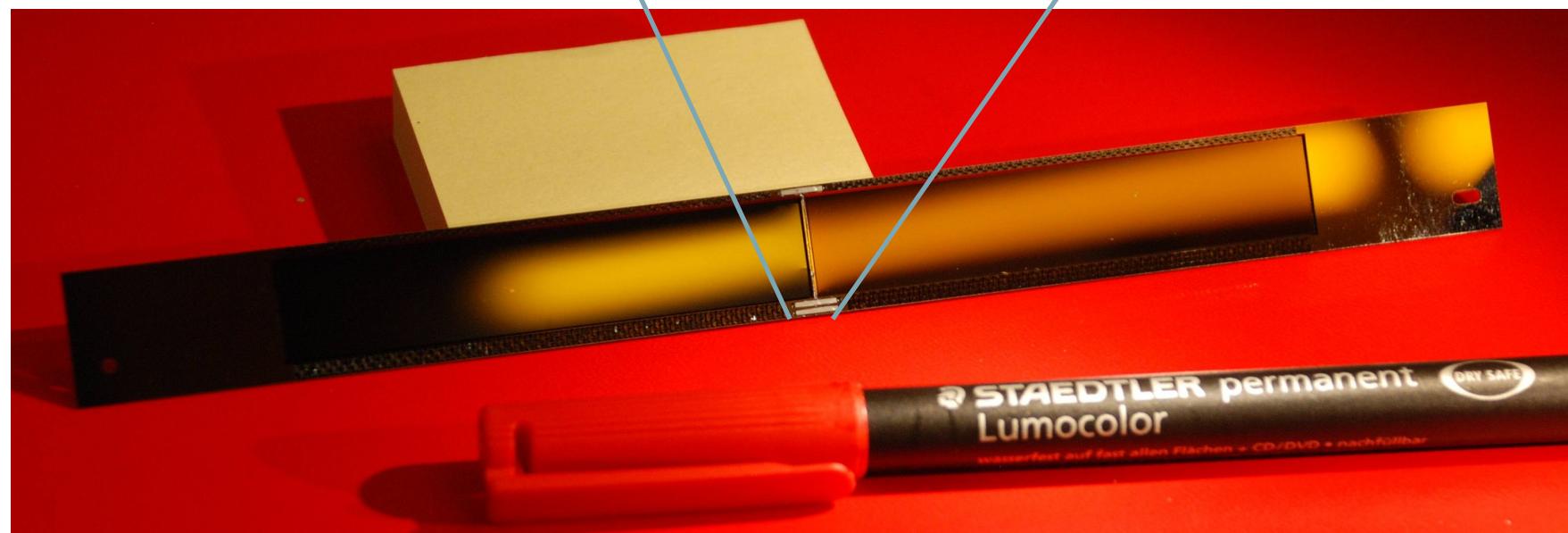
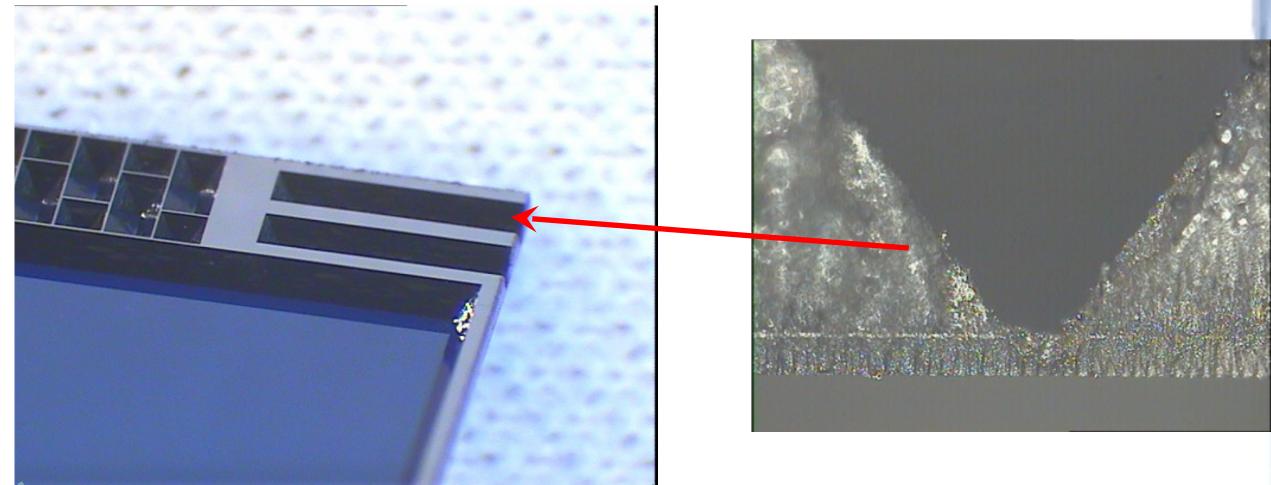


Thank you very much !

BACKUP slides

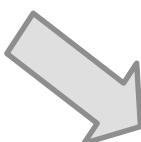
Micro joint between half-ladders

- butt joint between two half-ladders
- reinforced with 3 triangular ceramic inserts at the frame
- about $2 \times 300\mu\text{m}$ dead area per ladder

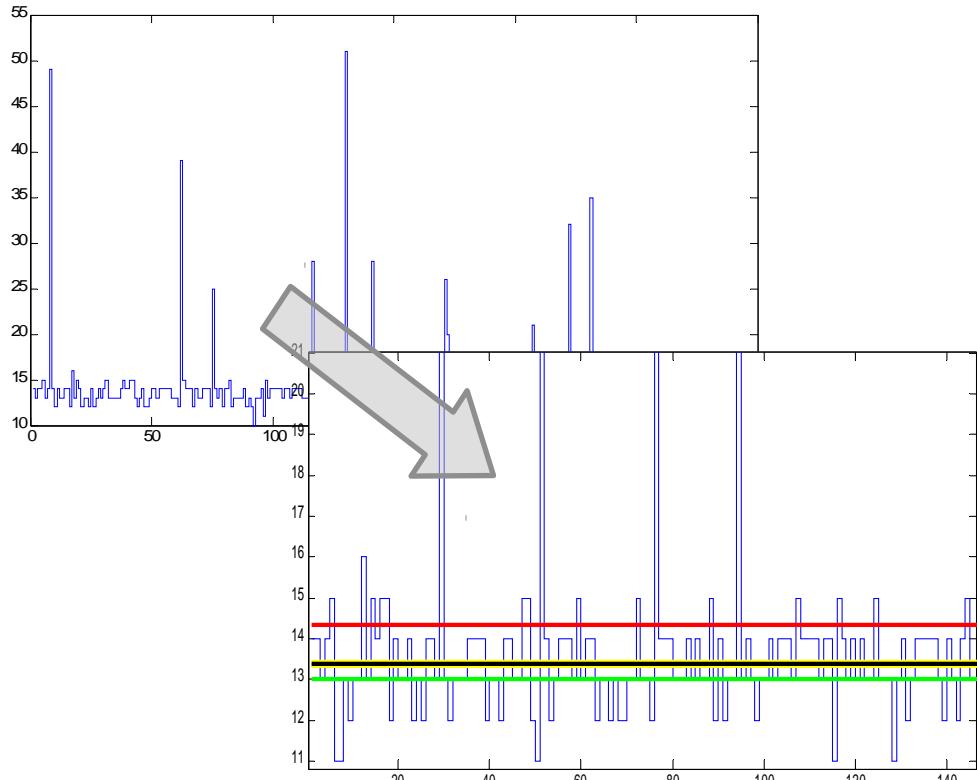


Common mode calculation

- Pickup noise, common to all pixels in row
- Possible techniques:
 - Simple average
 - ✓ + Easy hardware implementation
 - ✓ - Result is biased, especially for high occupancies (can be partially corrected offline)
 - Median estimator
 - ✓ + Unbiased
 - ✓ - Too resource hungry, difficult to implement in hardware within given constraints
 - Double parse average
 - ✓ +Unbiased
 - ✓ +Good resource compromise



$$\begin{aligned} \bullet \quad \widetilde{CM} &= \frac{\sum a_i}{N} \\ \bullet \quad CM &= \frac{\sum_{\{(a_i \geq \widetilde{CM} + Tr)\}} a_i}{N} \end{aligned}$$



the average is:	14.33
the median is:	13
the double average is:	13.38
the true common mode is:	13.4

- *Frame Header SOF (32 bit): <data type | flags| frame ID>*
 - data type (3 bit): [raw data or 0-supp. data]
 - flags, not used yet (13 bit)
 - frame ID (16 bit)

➔ will always be send at start of a new frame, independent of trigger
- *Row Header SOR (16 bit): <flag = 0 | row address | common mode>*
 - flag (1 bit): 0 ➔ row header
 - row address (9 bit)
 - common mode (6 bit)

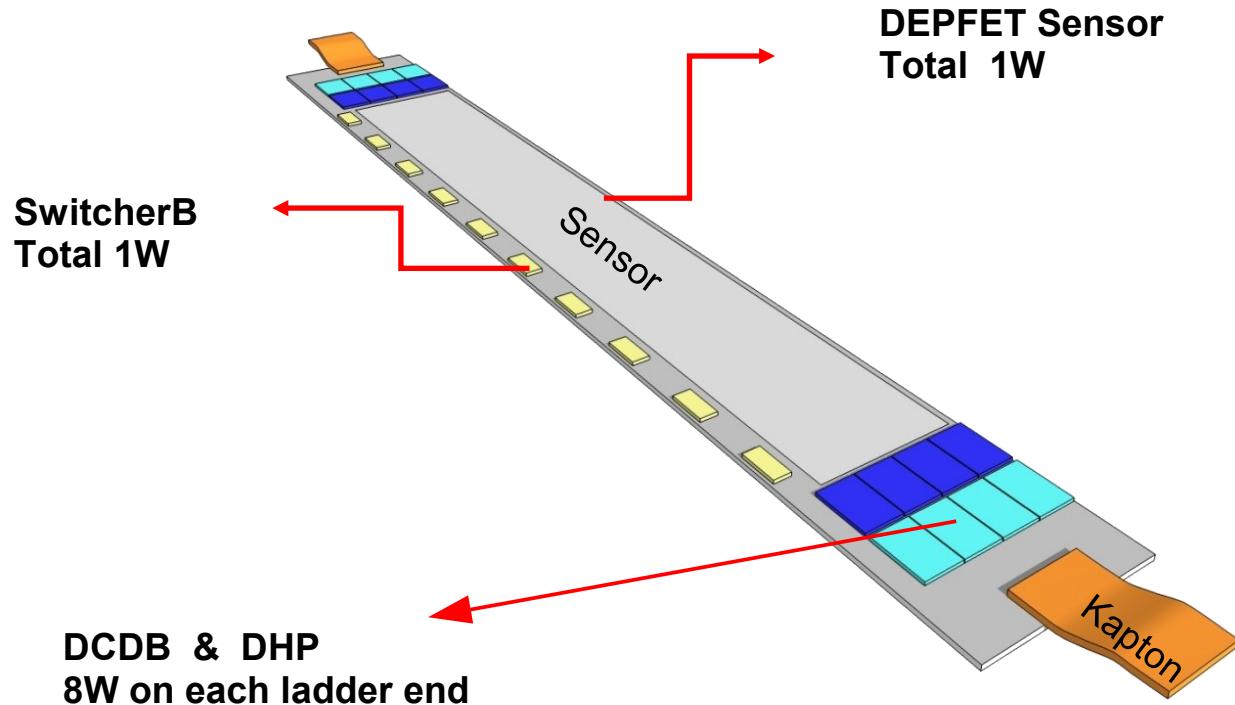
➔ will only be send if hit data for the active row is available
- *Data Word DW (16 bit): <flag = 1 | column address | ADC>*
 - flag (1 bit): 1 ➔ pixel data
 - column address (7 bit)
 - ADC (8 bit)

- *Typical data stream:*

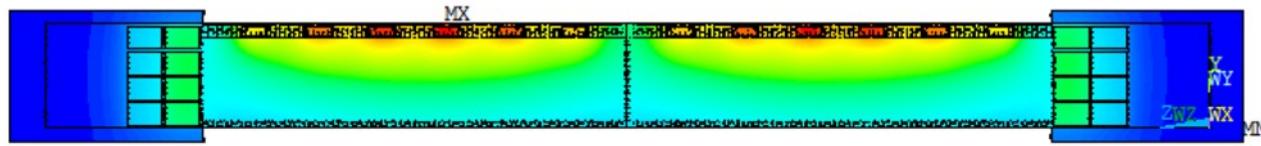
<SOF n><SOR m><DW i><DW i+x> ... <SOR m+y><DW j><DW j+y> ...
<SOF n+1> ...

- *SOF will be send for every frame independent of trigger*
- *SOR will be send only if corresponding row contains hits*
- *Data will be sorted*
 - Frame wise
 - Row wise
 - Column wise
- *Data form different DHPs will not be aligned*
 - Data per DHP (3% occupancy) \approx 4 kByte

Temperature budget



Support & cooling structure



Temperature distribution along the ladder

T_{env}=-5°C
T_{cb}=8°C

T SENSOR max=14°C
Delta T=4.7°C

